

**Search Notes**

Application/Control No.

10/565,162

Examiner

Sang Nguyen

Applicant(s)/Patent under  
Reexamination

CHANG ET AL.

Art Unit

2886

**SEARCHED**

Class	Subclass	Date	Examiner
356	432-444	12/23/2007	SN
	244		
	246		
	39		
	72-73		
250	559.01		
	559.09		
	206.1		
436	517		
	528		
422	82.05		
	61-63		
	67	12/23/2007	SN

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	12/23/2007	SN

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner